

$p_{\text{T}}^{\text{miss}}$ bin (GeV)	$p_{\text{T}}^{\text{miss}}$ CR yield N^{CR} (events)	Transfer factor \mathcal{T}	Background prediction \mathcal{B} (events)	Observed yield (events)	Exp. signal $m(\tilde{g}) = 1700$ GeV (events)
300–450	1191	0.198 ± 0.009	$236 \pm 7 \pm 16$	237	3.5 ± 0.1
450–600	320		$63.3 \pm 3.6 \pm 3.3$	67	4.3 ± 0.1
600–800	112		$22.2 \pm 2.0 \pm 1.9$	20	6.6 ± 0.1
800–1000	16		$3.2 \pm 0.8 \pm 0.5$	3	7.2 ± 0.1
1000–1200	2		$0.40 \pm 0.29 \pm 0.11$	3	7.2 ± 0.1
>1200	1		$0.20 \pm 0.20 \pm 0.06$	1	11.6 ± 0.1